

Search Notes



Application/Control No.

10/803,999

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

TAKAHASHI ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	271.1	5-29 -05	SJL
	278.1		
	270.1		
	944		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Structure Search for formula (I) of cl. #2	11-7 -05	SJL
Structure Search for formula (I-b) of cl. #5		